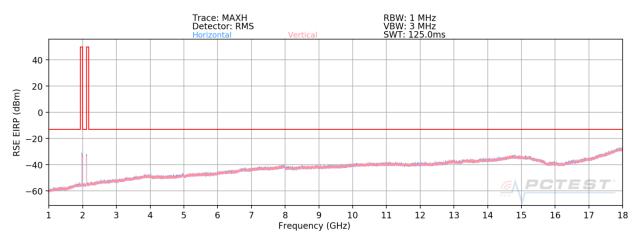
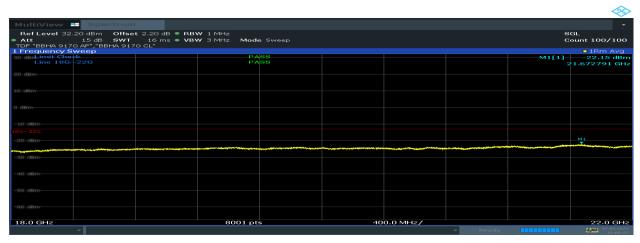


Plot 7-1299. Radiated spurious emission\_30 MHz to 1000 MHz (Multi Band\_B2\_5M+5M+5M\_3C\_High + B66\_5M+5M+5M\_3C\_Low)



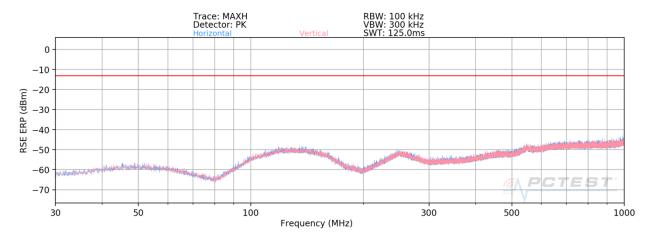
Plot 7-1300. Radiated spurious emission\_1 GHz to 18 GHz (Multi Band\_B2\_5M+5M+5M\_3C\_High + B66\_5M+5M+5M\_3C\_Low)



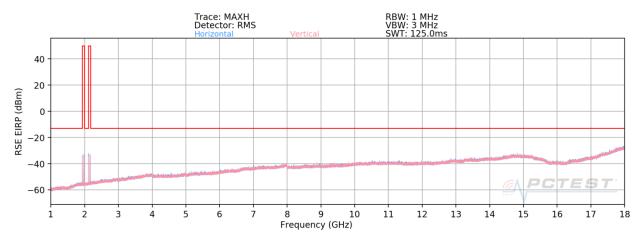
Plot 7-1301. Radiated spurious emission\_18 GHz to 22 GHz (Multi Band\_B2\_5M+5M+5M\_3C\_High + B66\_5M+5M+5M\_3C\_Low)

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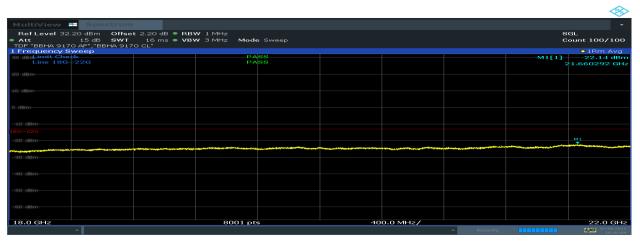




Plot 7-1302. Radiated spurious emission\_30 MHz to 1000 MHz (Multi Band\_B2\_5M+5M+5M\_3C - Non-contiguous + B66\_5M+5M+5M\_3C - Non-contiguous)



Plot 7-1303. Radiated spurious emission\_1 GHz to 18 GHz (Multi Band\_B2\_5M+5M+5M\_3C - Non-contiguous + B66\_5M+5M+5M\_3C - Non-contiguous)



Plot 7-1304. Radiated spurious emission\_18 GHz to 22 GHz (Multi Band\_B2\_5M+5M+5M\_3C - Non-contiguous + B66\_5M+5M+5M\_3C - Non-contiguous)

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Bandwidth (MHz):	B2_5MHz + B66_5MHz		
Frequency (MHz):	1 <sup>st</sup> Carrier : B2_1932.5 2 <sup>st</sup> Carrier : B66_2177.5		
Modulation Signal:	QPSK		

Frequency [MHz]	Ant. Pol. [H/V]	Antenna Heigh [cm]	Turntable azimuth [degree]	Analyzer Level [dBm]	AFCL [dBm]	Field Stength [dB \mu /m]	RSE EIRP [dBm]	Limit [dBm]	Margin [dB]
988.12	Н	140	120	-81.64	26.10	51.50	-43.77	-13.00	-30.77
989.47	V	180	150	-81.25	26.11	51.90	-43.37	-13.00	-30.37
17982.45	Н	180	50	-79.82	34.65	61.80	-33.40	-13.00	-20.40
17991.28	V	210	180	-80.03	34.65	61.60	-33.61	-13.00	-20.61

Table 7-256. Radiated transmitter Emission Table (Multi Band\_B2\_5M\_1C\_Low + B66\_5M\_1C\_High)

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# 7.9 Frequency Stability

## § 2.1055

### **Test Overview and Limit**

Frequency stability testing is performed in accordance with the guidelines of KDB 971168 D01 v03r01. The frequency stability of the transmitter is measured by:

- a.) **Temperature:** The temperature is varied from -30°C, +20°C and +50°C using an environmental chamber.
- b.) **Primary Supply Voltage:** The primary supply voltage is varied from 85% to 115% of the nominal value for DC powered equipment.

## **Test Description**

- 1. The carrier frequency of the transmitter is measured at room temperature (20°C to provide a reference).
- 2. The equipment is turned on in a "standby" condition for fifteen minutes before applying power to the transmitter. Measurement of the carrier frequency of the transmitter is made within one minute after applying power to the transmitter.
- 3. Frequency measurements are made -30°C, +20°C and +50°C. A period of at least one half-hour is provided to allow stabilization of the equipment at each temperature level.

### Limit

The frequency stability shall be sufficient to ensure that the fundamental emission stays within the authorized frequency block.

### **Test Setup**

The EUT was connected via an RF cable to a spectrum analyzer with the EUT placed inside an environmental chamber.

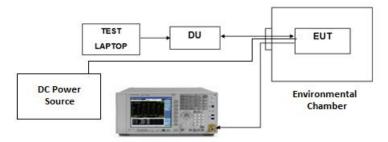


Figure 7-9. Test Instrument & Measurement Setup

### **Test Notes**

None.

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OPERATING FREQUENCY: 1,960,000,000 110.00 VAC REFERENCE VOLTAGE:

VOLTAGE	POWER	TEMP	FREQUENCY	Freq. Dev.	Deviation
(%)	(VAC)	<b>(</b> °C)	(Hz)	(Hz)	(%)
100 %		+ 20 (Ref)	1,960,029,967	0	0.0000000
100 %		- 30	1,960,029,957	-10	-0.0000005
100 %		- 20	1,960,029,960	-7	-0.0000004
100 %		- 10	1,960,029,963	-4	-0.0000002
100 %	110.00	0	1,960,029,968	1	0.0000001
100 %	110.00	+ 10	1,960,029,979	12	0.0000006
100 %		+ 20	1,960,029,967	0	0.0000000
100 %		+ 30	1,960,029,968	1	0.0000001
100 %		+ 40	1,960,029,961	-6	-0.0000003
100 %		+ 50	1,960,029,965	-2	-0.0000001
85 %	93.50	+ 20	1,960,029,970	3	0.0000002
115 %	126.50	+ 20	1,960,029,970	3	0.0000002

Table 7-257. Frequency Stability Data – Band 2\_5 MHz 1C Mid Channel

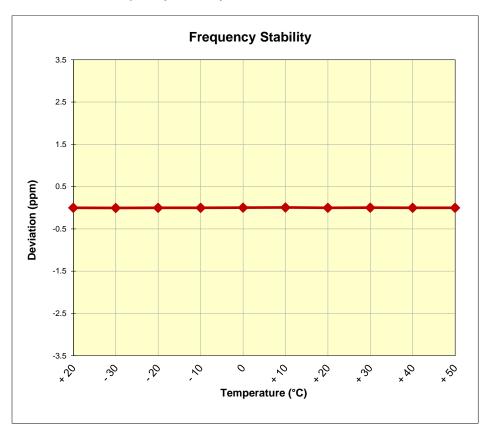


Figure 7-10. Frequency Stability Graph - Band 2\_5 MHz 1C Mid Channel

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OPERATING FREQUENCY: 2,145,000,000 REFERENCE VOLTAGE: 110.00 VAC

VOLTAGE	POWER	TEMP	FREQUENCY	Freq. Dev.	Deviation
(%)	(VAC)	<b>(</b> °C)	(Hz)	(Hz)	(%)
100 %		+ 20 (Ref)	2,145,029,970	0	0.0000000
100 %		- 30	2,145,029,953	-17	-0.0000008
100 %		- 20	2,145,029,959	-11	-0.0000005
100 %	110.00	- 10	2,145,029,961	-9	-0.0000004
100 %		0	2,145,029,969	-1	0.0000000
100 %	110.00	+ 10	2,145,029,967	-3	-0.0000001
100 %		+ 20	2,145,029,970	0	0.0000000
100 %		+ 30	2,145,029,965	-5	-0.0000002
100 %		+ 40	2,145,029,957	-13	-0.0000006
100 %		+ 50	2,145,029,961	-9	-0.0000004
85 %	93.50	+ 20	2,145,029,966	-4	-0.0000002
115 %	126.50	+ 20	2,145,029,941	-29	-0.0000014

Table 7-258. Frequency Stability Data - Band 66\_5 MHz 1C Mid Channel

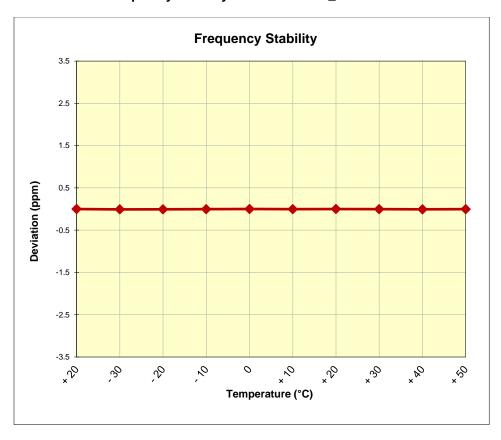


Figure 7-11. Frequency Stability Graph - Band 66\_5 MHz 1C Mid Channel

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#### CONCLUSION 8.0

The data collected relate only to the item(s) tested and show that the Samsung RRU(RF4437d)

FCC ID: A3LRF4437D-25D complies with all of the requirements of Part 24, and 27 FCC Rules.

FCC ID: A3LRF4437D-25D	PCTEST	MEASUREMENT REPORT	Approved by: Technical Manager
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## 9.0 APPENDIX A

### 9.1 Introduction (KDB 484596 Section 3 a)

The applicant takes full responsibility that the test data as referenced FCC ID : A3LRF4437D-25C represents compliance for FCC ID : A3LRF4437D-25D

# 9.2 Explain the Differences (KDB 484596 Section 3 b)

FCC ID: A3LRF4437D-25C is powered by DC voltage source. For FCC ID: A3LRF4437D-25D is powered by AC voltage source which is only different power supply condition that no affect to RF parameters because other components are identical except for power supply.

# 9.3 Spot Check Verification Data (KDB 484596 Section 3 c)

Spot check verification was adopted to the following two test cases to check whether it is changed by power supply difference. As a result, the For FCC ID: A3LRF4437D-25D And For FCC ID: A3LRF4437D-25C test result can be identical because both are using same RF components.

- Case #1 : B2\_5M\_1C - Case #2 : B66\_5M\_1C

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Channel	Port	OBW (MHz)				
Channel	FUIL	QPSK	16QAM	64QAM	256QAM	
	0	4.49	4.48	4.49	4.49	
Low	1	4.49	4.48	4.49	4.49	
Low	2	4.48	4.49	4.49	4.49	
	3	4.48	4.48	4.50	4.49	
	0	4.49	4.48	4.49	4.49	
Middle	1	4.49	4.48	4.50	4.49	
ivildale	2	4.48	4.48	4.50	4.49	
	3	4.48	4.48	4.50	4.49	
	0	4.49	4.49	4.50	4.49	
High	1	4.48	4.48	4.50	4.49	
High	2	4.49	4.48	4.49	4.49	
	3	4.48	4.48	4.50	4.49	

Table 9-1. Occupied Bandwidth Summary Data (B2\_5M\_1C)

Chanal	Dowt	OBW (MHz)				
Channel	Port	QPSK	16QAM	64QAM	256QAM	
	0	4.48	4.48	4.49	4.49	
Low	1	4.48	4.48	4.49	4.50	
Low	2	4.48	4.48	4.49	4.49	
	3	4.48	4.48	4.49	4.49	
	0	4.49	4.49	4.51	4.50	
Middle	1	4.48	4.49	4.50	4.50	
ivildale	2	4.48	4.49	4.50	4.50	
	3	4.48	4.48	4.50	4.50	
	0	4.49	4.48	4.50	4.50	
Lligh	1	4.49	4.48	4.50	4.50	
High	2	4.49	4.49	4.50	4.50	
	3	4.49	4.49	4.51	4.50	

Table 9-2. Occupied Bandwidth Summary Data (B66\_5M\_1C)

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Low Channel	Port	QPSK	16QAM	64QAM	256QAM
	0	39.48	39.46	39.45	39.44
Conducted Average	1	39.46	39.37	39.47	39.48
Power (dBm)	2	39.54	39.61	39.64	39.63
	3	39.51	39.67	39.64	39.67
Total MIMO Conducted Power (mW)		35630.39	35889.91	36070.64	36113.41
Total MIMO Conducted Power (dBm)		45.52	45.55	45.57	45.58

Table 9-3. Conducted Average Output Power Table (B2\_5M\_1C - Low Channel)

Middle Channel	Port	QPSK	16QAM	64QAM	256QAM
	0	39.49	39.49	39.42	39.50
Conducted Average	1	39.47	39.50	39.50	39.50
Power (dBm)	2	39.50	39.57	39.57	39.53
	3	39.55	39.67	39.63	39.70
Total MIMO Conducted Power (mW)		35671.39	36130.14	35903.00	36131.85
Total MIMO Conducted Power (dBm)		45.52	45.58	45.55	45.58

Table 9-4. Conducted Average Output Power Table (B2\_5M\_1C - Middle Channel)

High Channel	Port	QPSK	16QAM	64QAM	256QAM
	0	39.51	39.52	39.43	39.49
Conducted Average	1	39.58	39.55	39.51	39.46
Power (dBm)	2	39.57	39.59	39.54	39.54
	3	39.68	39.60	39.57	39.59
Total MIMO Conducted Power (mW)		36358.25	36188.60	35755.36	35816.92
Total MIMO Conducted Power (dBm)		45.61	45.59	45.53	45.54

Table 9-5. Conducted Average Output Power Table (B2\_5M\_1C - High Channel)

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Low Channel	Port	QPSK	16QAM	64QAM	256QAM
	0	40.40	40.37	40.43	40.37
Conducted Average	1	40.26	40.22	40.23	40.27
Power (dBm)	2	40.54	40.62	40.62	40.63
	3	40.45	40.43	40.42	40.45
Total MIMO Conducted Power (mW)		43997.49	43984.24	44134.58	44183.60
Total MIMO Conducted Power (dBm)		46.43	46.43	46.45	46.45

Table 9-6. Conducted Average Output Power Table (B66\_5M\_1C - Low Channel)

Middle Channel	Port	QPSK	16QAM	64QAM	256QAM
	0	40.69	40.61	40.68	40.63
Conducted Average	1	40.53	40.52	40.61	40.55
Power (dBm)	2	40.74	40.85	40.81	40.85
	3	40.62	40.62	40.70	40.62
Total MIMO Conducted Power (mW)		46412.13	46476.37	47002.33	46607.62
Total MIMO Conducted Power (dBm)		46.67	46.67	46.72	46.68

Table 9-7. Conducted Average Output Power Table (B66\_5M\_1C - Middle Channel)

High Channel	Port	QPSK	16QAM	64QAM	256QAM
	0	40.75	40.73	40.77	40.75
Conducted Average	1	40.42	40.42	40.44	40.41
Power (dBm)	2	40.72	40.69	40.72	40.65
	3	40.70	40.67	40.72	40.64
Total MIMO Conducted Power (mW)		46452.60	46235.86	46612.53	46077.34
Total MIMO Conducted Power (dBm)		46.67	46.65	46.69	46.63

Table 9-8. Conducted Average Output Power Table (B66\_5M\_1C - High Channel)

FCC ID: A3LRF4437D-25D	PCTEST ENGINEERING LABORATORY, INC.	MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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Channel	Port	Measured Range (MHz)	Max. Value (dBm)	Limit (dBm)
	0	1929 to 1930	-27.75	-19.02
	0	1928 to 1929	-25.31	-19.02
	1	1929 to 1930	-26.95	-19.02
Low	1	1928 to 1929	-25.34	-19.02
LOW	2	1929 to 1930	-27.54	-19.02
	2	1928 to 1929	-25.38	-19.02
	3	1929 to 1930	-28.25	-19.02
	3	1928 to 1929	-25.34	-19.02
	0	1990 to 1991	-28.59	-19.02
	0	1991 to 1992	-25.72	-19.02
	1	1990 to 1991	-28.11	-19.02
High	1	1991 to 1992	-25.81	-19.02
riigii	2	1990 to 1991	-28.03	-19.02
	2	1991 to 1992	-25.77	-19.02
	3	1990 to 1991	-28.65	-19.02
	3	1991 to 1992	-25.33	-19.02

Table 9-9. Band Edge Emission Summary Data (B2\_5M\_1C)

Channel	Port	Measured Range (MHz)	Max. Value (dBm)	Limit (dBm)
	0	2109 to 2110	-26.02	-19.02
	0	2108 to 2109	-35.09	-19.02
	1	2109 to 2110	-25.80	-19.02
Low	1	2108 to 2109	-33.04	-19.02
LOW	2	2109 to 2110	-26.44	-19.02
	2	2108 to 2109	-31.85	-19.02
	3	2109 to 2110	-27.05	-19.02
	3	2108 to 2109	-36.49	-19.02
	0	2180 to 2181	-32.85	-19.02
	0	2181 to 2182	-24.44	-19.02
	1	2180 to 2181	-31.62	-19.02
Lliah	1	2181 to 2182	-23.78	-19.02
High	2	2180 to 2181	-30.82	-19.02
	2	2181 to 2182	-25.87	-19.02
	3	2180 to 2181	-31.61	-19.02
	3	2181 to 2182	-26.70	-19.02

Table 9-10. Band Edge Emission Summary Data (B66\_5M\_1C)

FCC ID: A3LRF4437D-25D	PCTEST ENGINEERING LABORATORY, INC.	MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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Channel	Port	Measurement Range	Level (dBm)	Limit (dBm)	Worst Margin (dB)
		9 kHz to 150 kHz	-64.11	-49.02	-15.09
		150 kHz to 30 MHz	-62.19	-39.02	-23.17
		30 MHz to 1 GHz	-53.59	-29.02	-24.57
	0	1 GHz to 1.928 GHz	-25.63	-19.02	-6.61
		1.992 GHz to 6 GHz	-27.57	-19.02	-8.55
		6 GHz to 22 GHz	-25.83	-19.02	-6.81
		9 kHz to 150 kHz	-62.94	-49.02	-13.92
		150 kHz to 30 MHz	-59.99	-39.02	-20.97
	,	30 MHz to 1 GHz	-50.61	-29.02	-21.59
	1	1 GHz to 1.928 GHz	-28.00	-19.02	-8.98
		1.992 GHz to 6 GHz	-26.00	-19.02	-6.98
Low		6 GHz to 22 GHz	-26.04	-19.02	-7.02
Low	2	9 kHz to 150 kHz	-64.69	-49.02	-15.67
		150 kHz to 30 MHz	-61.52	-39.02	-22.50
		30 MHz to 1 GHz	-50.19	-29.02	-21.17
		1 GHz to 1.928 GHz	-26.06	-19.02	-7.04
		1.992 GHz to 6 GHz	-24.34	-19.02	-5.32
		6 GHz to 22 GHz	-26.38	-19.02	-7.36
		9 kHz to 150 kHz	-61.49	-49.02	-12.47
		150 kHz to 30 MHz	-60.90	-39.02	-21.88
		30 MHz to 1 GHz	-50.76	-29.02	-21.74
	3	1 GHz to 1.928 GHz	-28.14	-19.02	-9.12
		1.992 GHz to 6 GHz	-27.17	-19.02	-8.15
		6 GHz to 22 GHz	-26.09	-19.02	-7.07

Table 9-11. Conducted Spurious Emission Summary Data (B2\_5M\_1C)

FCC ID: A3LRF4437D-25D	PCTEST*	MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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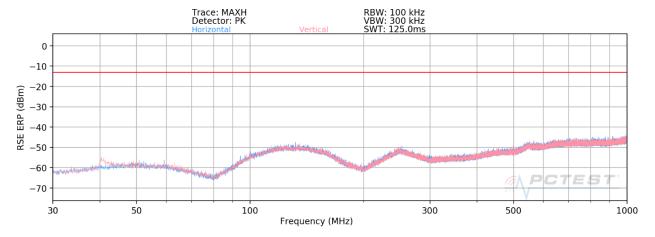


Channel	Port	Measurement Range	Level (dBm)	Limit (dBm)	Worst Margin (dB)
		9 kHz to 150 kHz	-60.86	-49.02	-11.84
		150 kHz to 30 MHz	-58.06	-39.02	-19.04
	0	30 MHz to 1 GHz	-53.92	-29.02	-24.90
	0	1 GHz to 2.108 GHz	-31.05	-19.02	-12.03
		2.182 GHz to 6 GHz	-28.32	-19.02	-9.30
		6 GHz to 22 GHz	-24.96	-19.02	-5.94
		9 kHz to 150 kHz	-60.30	-49.02	-11.28
		150 kHz to 30 MHz	-58.26	-39.02	-19.24
	1	30 MHz to 1 GHz	-51.29	-29.02	-22.27
	I	1 GHz to 2.108 GHz	-30.48	-19.02	-11.46
		2.182 GHz to 6 GHz	-26.29	-19.02	-7.27
Low		6 GHz to 22 GHz	-24.77	-19.02	-5.75
Low	2	9 kHz to 150 kHz	-61.37	-49.02	-12.35
		150 kHz to 30 MHz	-59.35	-39.02	-20.33
		30 MHz to 1 GHz	-50.82	-29.02	-21.80
		1 GHz to 2.108 GHz	-30.45	-19.02	-11.43
		2.182 GHz to 6 GHz	-24.77	-19.02	-5.75
		6 GHz to 22 GHz	-25.17	-19.02	-6.15
		9 kHz to 150 kHz	-60.92	-49.02	-11.90
		150 kHz to 30 MHz	-57.80	-39.02	-18.78
	3	30 MHz to 1 GHz	-50.68	-29.02	-21.66
		1 GHz to 2.108 GHz	-30.64	-19.02	-11.62
		2.182 GHz to 6 GHz	-27.27	-19.02	-8.25
		6 GHz to 22 GHz	-25.51	-19.02	-6.49

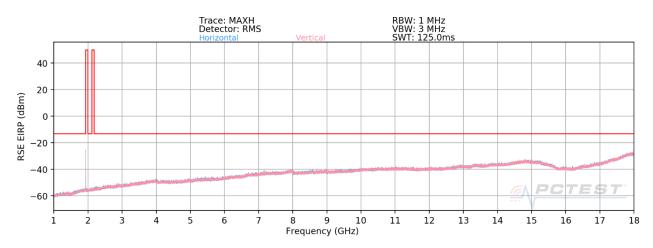
Table 9-12. Conducted Spurious Emission Summary Data (B66\_5M\_1C)

FCC ID: A3LRF4437D-25D	PCTEST*	MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
Test Report S/N:	Test Dates:	EUT Type:		Page 427 of 430
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© 2021 PCTEST				PK-QP-16-14 Rev.01

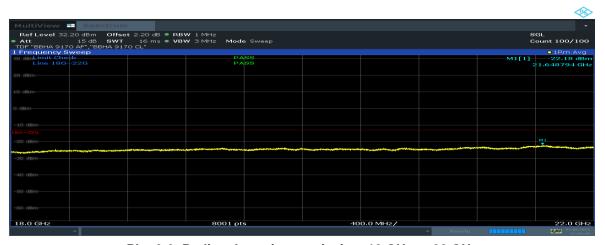




Plot 9-1. Radiated spurious emission\_30 MHz to 1000 MHz (B2\_5M\_1C\_Low Channel)



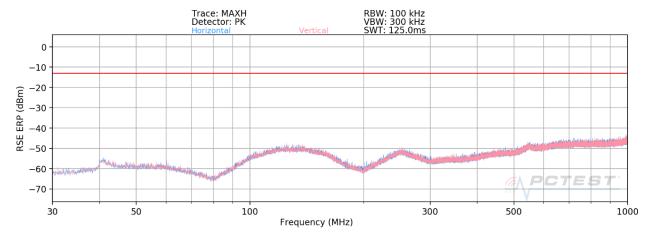
Plot 9-2. Radiated spurious emission\_1 GHz to 18 GHz (B2\_5M\_1C\_Low Channel)



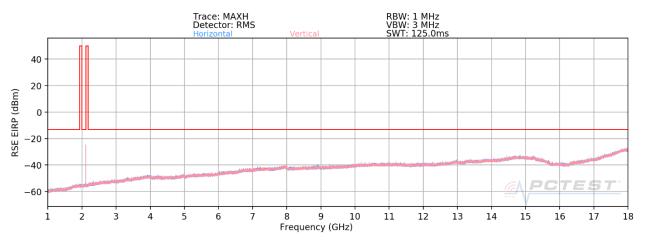
Plot 9-3. Radiated spurious emission\_18 GHz to 22 GHz (B2\_5M\_1C\_Low Channel)

FCC ID: A3LRF4437D-25D	PCTEST ENGINEERING LABORATORY, INC.	MEASUREMENT REPORT	Approved by: Technical Manager
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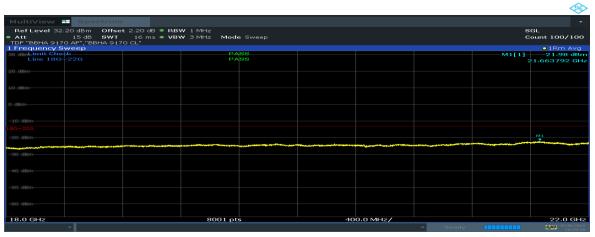




Plot 9-4. Radiated spurious emission\_30 MHz to 1000 MHz (B66\_5M\_1C\_Low Channel)



Plot 9-5. Radiated spurious emission\_1 GHz to 18 GHz (B66\_5M\_1C\_Low Channel)



Plot 9-6. Radiated spurious emission\_18 GHz to 22 GHz (B66 5M 1C Low Channel)

FCC ID: A3LRF4437D-25D	PCTEST ENGINEERING LABORATORY, INC.	MEASUREMENT REPORT	Approved by: Technical Manager
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# 9.4 Reference Section (KDB 484596 Section 3 d)

A matrix has been provided the source data for rule part, frequency range, and emission designator as required by KDB 484596:

Rule Part	Frequency Range(MHz)	Emission Designator	Source Data FCC ID	Exhibit Name(s)
24E	1930.0 – 1990.0	4M48G7D 4M48W7D 9M44G7D 9M45W7D 14M4G7D 14M4W7D 17M9G7D 17M9W7D 23M7G7D 23M7W7D 28M6G7D 28M6W7D		
27	2110.0 – 2180.0	4M48G7D 4M49W7D 9M44G7D 9M46W7D 14M4G7D 14M4W7D 19M4G7D 19M4W7D 23M7G7D 23M7W7D 28M6G7D 28M7W7D 33M5G7D 33M6W7D 38M6G7D 38M6G7D	A3LRF4437D-25C	15. FCC RF Test Report 16. MPE Test Report

FCC ID: A3LRF4437D-25D	PCTEST*	MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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